


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/767,499	NICHTAWITZ ET AL.	
	Examiner	Art Unit	
	Devin Hanan	3745	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS-REFERENCE(S)					
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
415	163			415	1				
INTERNATIONAL CLASSIFICATION									
F	0	3	B	1/04					
				/					
				/					
				/					
				/					
<i>Devin Hanan</i> 1/18/06 Devin Hanan 1/18/2006 (Assistant Examiner) (Date)				<i>Edward K. Look</i> 1/21/06 EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date)				Total Claims Allowed: 52	
<i>H. Conner</i> 1-26-06 (Legal Instruments Examiner) (Date)								O G Print Claim(s) 1	O G Print Fig. 3A, 3B 3

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
1	1	30	31	61	91	121	181
2	2	31	32	62	92	122	182
3	3	32	33	63	93	123	183
4	4	33	34	64	94	124	184
5	5	35	35	65	95	125	185
6	6	34	36	66	96	126	186
7	7	36	37	67	97	127	187
8	8	37	38	68	98	128	188
9	9	38	39	69	99	129	189
10	10	39	40	70	100	130	190
12	11	40	41	71	101	131	191
11	12	41	42	72	102	132	192
13	13	42	43	73	103	133	193
14	14	43	44	74	104	134	194
15	15	44	45	75	105	135	195
16	16	45	46	76	106	136	196
17	17	47	47	77	107	137	197
18	18	46	48	78	108	138	198
19	19	48	49	79	109	139	199
	20	49	50	80	110	140	200
20	21	50	51	81	111	141	201
21	22	51	52	82	112	142	202
23	23	52	53	83	113	143	203
22	24		54	84	114	144	204
24	25		55	85	115	145	205
25	26		56	86	116	146	206
26	27		57	87	117	147	207
27	28		58	88	118	148	208
28	29		59	89	119	149	209
29	30		60	90	120	150	210